

Search Notes

Application/Control No.

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Examiner

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Applicant(s)/Patent under
Reexamination

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Art Unit

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SEARCHED

Class	Subclass	Date	Examiner
348	239, 333.02	8/19/2007	NT

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST search (USPAT, PGPUB, JPO, EPO, DERWENT, IBM_TDB)	8/19/2007	NT
348/333.01-333.12 (text search - see search history printout)	8/19/2007	NT
382/294 (text search - see search history printout)	8/20/2007	NT
Inventorship search	8/20/2007	NT